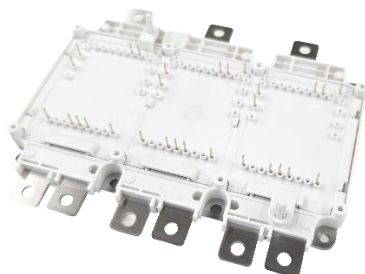


PRELIMINARY DATASHEET SCSS0022EVD120m23

EVD-Type three-phase 1.2kV SiC module



$V_{DSS} = 1200\text{ V}$

$R_{DSon} = 2.2\text{ m Ohm @ } I_D = 600\text{ A}$

- *m23 generation SiC MOSFET chips*
- *Ultra-low R_{DSon}*
- *Low switching losses, Q_g and Cr_{ss}*
- *Low inductance module $< 9\text{ nH}$*
- *$T_{vj,op} = 175^\circ\text{C}$*
- *4.2kV DC 1 sec insulation*
- *Compact design*
- *Direct cooled PinFin baseplate*
- *High performance Si_3N_4 ceramic substrates*
- *Guiding elements for PCB and cooler assembly*
- *Integrated NTC temperature sensor*
- *RoHS compliant*

Maximum ratings ¹

PARAMETER	SYMBOL	CONDITIONS	MIN	MAX	UNIT
Drain – source voltage	V_{DSS}	$V_{GS} \leq 0\text{ V}$, $T_{vj} = 25^\circ\text{C}$		1200	V
Continuous drain and source current	I_D , I_S	$T_F = 60^\circ\text{C}$, $V_{GS} = 18\text{ V}$, $T_{vj} = 175^\circ\text{C}$		545	A
Peak drain and source current	I_{DM} , I_{SM}	$t_p = 1\text{ ms}$, limited by $T_{vj,max}$		1200	A
Gate-source voltage (DC)	V_{GSS}		-8	22	V
Gate-source surge voltage	$V_{GSS\text{ surge}}$	$t_{\text{surge}} < 300\text{ ns}$	-10	25	V
Recommended gate voltage	V_{GS}		-5	18	V
Surge current				TBD	A
MOSFET SCSOA	t_{psc}	$V_{DS} = 800\text{ V}$, $V_{GSon} = 18\text{ V}$, $T_{vj} < 175^\circ\text{C}$		TBD	μs
Isolation voltage	V_{isol}	RMS, 1 s, $f = 50\text{ Hz}$		4200	V
Junction operating temperature	$T_{vj(op)}$		-40	175	$^\circ\text{C}$
Storage temperature	T_{stg}		-40	125	$^\circ\text{C}$
Mounting torques for module mounting ²	M	Screw M4 baseplate to heatsink	1.8	2.2	Nm
Max pressure in cooling circuit	p	$T_{\text{baseplate}} < 40^\circ\text{C}$		2.5	bar
		$T_{\text{baseplate}} > 40^\circ\text{C}$		2.0	bar



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¹ Maximum rated values indicate limits beyond which damage to the device may occur per IEC 60747

² For details, please refer to the mounting instructions.



MOSFET³

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNIT
Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS} \leq 0 \text{ V}$, $I_D = 1.5 \text{ mA}$, $T_{vj} = -40 \dots 25^\circ\text{C}$	1200			V
Static drain-source on-state resistance ⁴	$R_{DS(on)}$	$I_D = 600 \text{ A}$, $V_{GS} = 18 \text{ V}$		$T_{vj} = 25^\circ\text{C}$ 2.2	2.7	$\text{m}\Omega$
				$T_{vj} = 175^\circ\text{C}$ 4		$\text{m}\Omega$
Zero gate voltage drain current	I_{DSS}	$V_{DS} = 1200 \text{ V}$, $V_{GS} = 0 \text{ V}$		$T_{vj} = 25^\circ\text{C}$ 6	60	μA
				$T_{vj} = 175^\circ\text{C}$ 60		μA
Gate leakage current	I_{GSS}	$V_{GS} = +22 / -10 \text{ V}$	-300		300	nA
Gate-emitter threshold voltage	$V_{GS(th)}$	$V_{GS} = V_{DS}$, $I_D = 30 \text{ mA}$		$T_{vj} = 25^\circ\text{C}$ 2.25	2.75	V
				$T_{vj} = 175^\circ\text{C}$ 2		V
Gate charge	Q_G	$I_D = 600 \text{ A}$, $V_{DS} = 800 \text{ V}$, $V_{GS} = -5 \text{ V} \dots 18 \text{ V}$		1.2		μC
Input capacitance	C_{iss}	$V_{DS} = 800 \text{ V}$, $V_{GS} = 0 \text{ V}$, $f = 100 \text{ kHz}$, $T_{vj} = 25^\circ\text{C}$		35.6		nF
Output capacitance	C_{oss}			2.4		nF
Reverse transfer capacitance	C_{rss}			0.18		nF
Internal gate resistor	R_{Gint}	Per switch		0.4		Ω
Turn-on delay time	$t_{d(on)}$	$V_{CC} = 800 \text{ V}$, $I_D = 600 \text{ A}$, $R_G = 4 \Omega$, $V_{GS} = -5 / +18 \text{ V}$, $L_S = 30 \text{ nH}$, inductive load		$T_{vj} = 25^\circ\text{C}$ 40		ns
				$T_{vj} = 125^\circ\text{C}$ 30		ns
				$T_{vj} = 175^\circ\text{C}$ 25		ns
Rise time	t_r			$T_{vj} = 25^\circ\text{C}$ 60		ns
				$T_{vj} = 125^\circ\text{C}$ 50		ns
				$T_{vj} = 175^\circ\text{C}$ 50		ns
Turn-off delay time	$t_{d(off)}$	$V_{CC} = 800 \text{ V}$, $I_D = 600 \text{ A}$, $R_G = 7 \Omega$, $V_{GS} = -5 / +18 \text{ V}$, $L_S = 30 \text{ nH}$, inductive load		$T_{vj} = 25^\circ\text{C}$ 370		ns
				$T_{vj} = 125^\circ\text{C}$ 430		ns
				$T_{vj} = 175^\circ\text{C}$ 460		ns
Fall time	t_f			$T_{vj} = 25^\circ\text{C}$ 70		ns
				$T_{vj} = 125^\circ\text{C}$ 70		ns
				$T_{vj} = 175^\circ\text{C}$ 70		ns
Turn-on switching energy	E_{on}	$V_{CC} = 800 \text{ V}$, $I_D = 600 \text{ A}$, $R_G = 4 \Omega$, $V_{GS} = -5 / +18 \text{ V}$, $L_S = 30 \text{ nH}$, inductive load		$T_{vj} = 25^\circ\text{C}$ 34		mJ
				$T_{vj} = 125^\circ\text{C}$ 33.5		mJ
				$T_{vj} = 175^\circ\text{C}$ 34		mJ
Turn-off switching energy	E_{off}	$V_{CC} = 800 \text{ V}$, $I_D = 600 \text{ A}$, $R_G = 7 \Omega$, $V_{GS} = -5 / +18 \text{ V}$, $L_S = 30 \text{ nH}$, inductive load		$T_{vj} = 25^\circ\text{C}$ 37		mJ
				$T_{vj} = 125^\circ\text{C}$ 40		mJ
				$T_{vj} = 175^\circ\text{C}$ 41		mJ
Short circuit current	I_{SC}	$t_{PCS} \leq 1.5 \mu\text{s}$, $V_{GE} = 18 \text{ V}$, $T_{vj} = 175^\circ\text{C}$, $V_{CC} = 800 \text{ V}$, $V_{DSM \text{ chip}} \leq 1200 \text{ V}$		TBD		A

³ Characteristic values according to IEC 60747-9

⁴ Given at chip level

Body Diode (MOSFET)⁵

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNIT
Drain-source reverse voltage ⁶	V_{SD}	$I_D = -600 \text{ A}$, $V_{GS} = 18 \text{ V}$	$T_{vj} = 25 \text{ °C}$	5.4		V
			$T_{vj} = 175 \text{ °C}$	4.8		V
MOSFET peak forward recovery current	I_{frm}	$V_R = 800 \text{ V}$, $I_{SD} = 600 \text{ A}$, $di/dt = 12.2 \text{ kA}/\mu\text{s}$, $R_G = 4 \text{ }\Omega$, $V_{GS} = -5 / +18 \text{ V}$, $L_s = 30 \text{ nH}$, inductive load	$T_{vj} = 25 \text{ °C}$	216		A
			$T_{vj} = 125 \text{ °C}$	354		A
			$T_{vj} = 175 \text{ °C}$	495		A
MOSFET forward recovery charge	Q_f		$T_{vj} = 25 \text{ °C}$	9.6		μC
			$T_{vj} = 125 \text{ °C}$	22.9		μC
			$T_{vj} = 175 \text{ °C}$	37.7		μC
MOSFET forward recovery time	t_{fr}		$T_{vj} = 25 \text{ °C}$	70		ns
			$T_{vj} = 125 \text{ °C}$	97		ns
			$T_{vj} = 175 \text{ °C}$	110		ns
MOSFET forward recovery energy	E_{fr}		$T_{vj} = 25 \text{ °C}$	6.8		mJ
			$T_{vj} = 125 \text{ °C}$	15		mJ
			$T_{vj} = 175 \text{ °C}$	24.1		mJ

Package properties ⁷

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNIT
Thermal resistance junction to fluid	$R_{th(j-f)}$	Per switch, Coolant 50% glycol, 50% water, 10 l/min, dp < 90 mbar		0.097		K/W
Comparative tracking index	CTI		400			
Module stray inductance	$L_{s \text{ CE}}$	Per switch		8.5		nH
Resistance, terminal chip	$R_{CC'+EE'}$	Per switch	$T_{vj} = 25 \text{ °C}$	0.5		m Ω
			$T_{vj} = 125 \text{ °C}$			m Ω
			$T_{vj} = 175 \text{ °C}$			m Ω
Material of module baseplate		Ni + Cu Nickel plated Cu baseplate				
Internal isolation		Si_3N_4 Basic insulation (class 1, IEC 61140)				

⁵ Characteristic values according to IEC 60747-8

⁶ Given at chip level

⁷ Package and mechanical properties according to IEC 60747-15



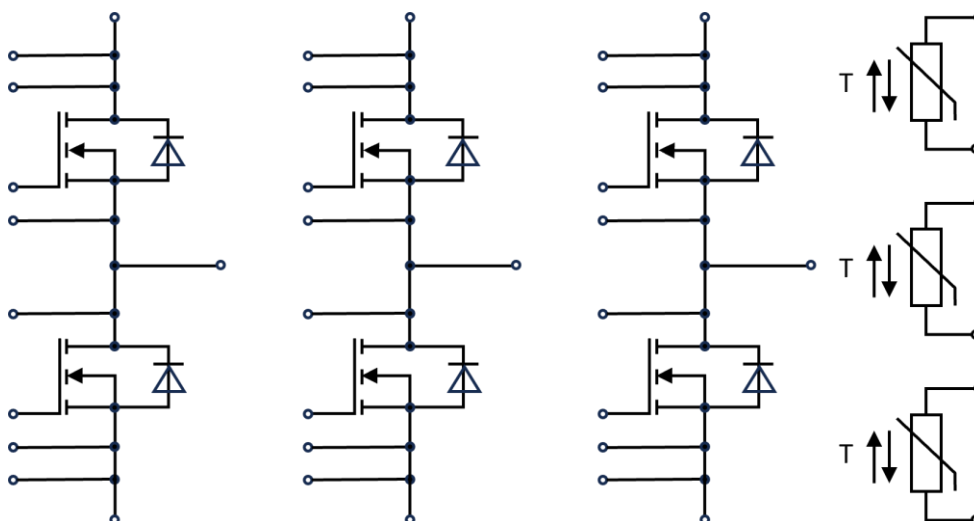
Mechanical properties

PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	UNIT
Dimensions	L x W x H	Typical		152 x 62 x 17			mm ³
Clearance distance in air	da	According to IEC 60664-1 and EN 50124-1	Terminal to base:	4.5			mm
			Terminal to terminal:	4.5			mm
Surface creepage distance	ds	According to IEC 60664-1 and EN 50124-1	Terminal to base:	9.0			mm
			Terminal to terminal:	9.0			mm
Mass	m				720		g

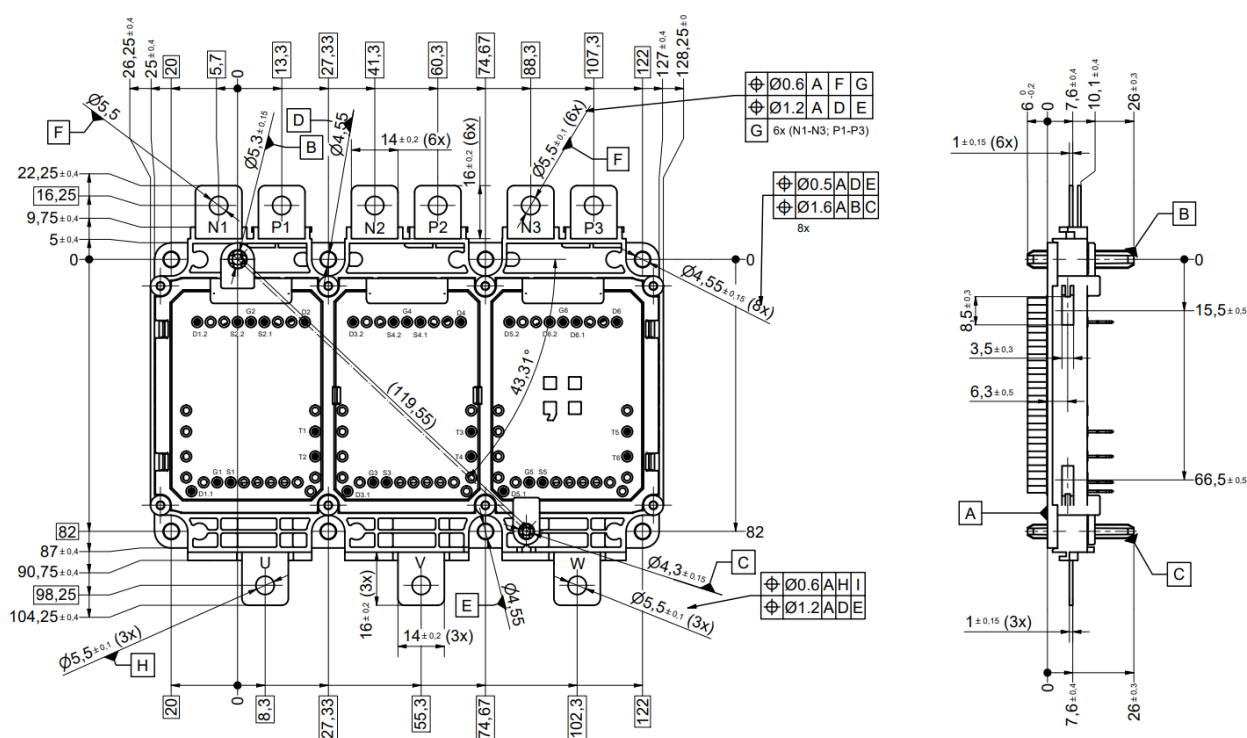
NTC Thermistor

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNIT
Rated resistance	R ₂₅	T _c = 25 °C		5		kΩ
R100	R ₁₀₀	T _c = 100 °C	468		518	Ω
B-value B	B _{25/50}	$R_2 = R_{25} \exp [B_{25/50}(1/T_2 - 1/(298.15K))]$		3375		K
B-value B	B _{25/50}	$R_2 = R_{25} \exp [B_{25/50}(1/T_2 - 1/(298.15K))]$		3411		K
Rated resistance	B _{25/100}	$R_2 = R_{25} \exp [B_{25/100}(1/T_2 - 1/(298.15K))]$		3433		K

Electrical configuration



Outline drawing



This is an electrostatic sensitive device.

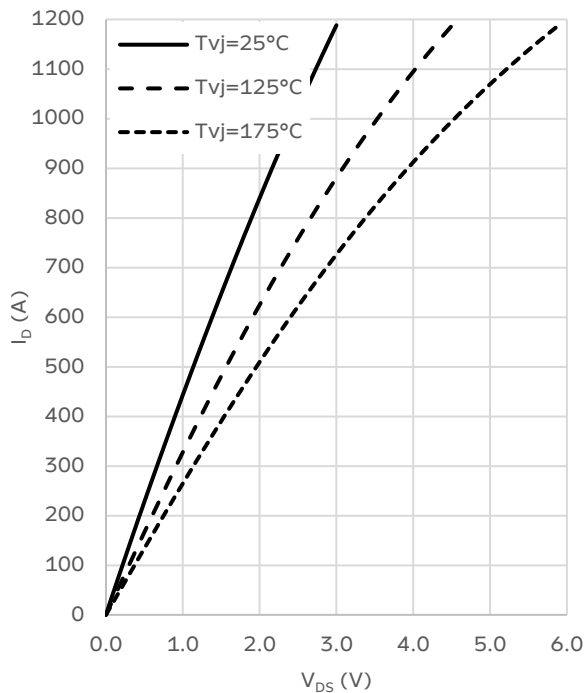
This product has been designed and qualified for automotive level.



Characteristics

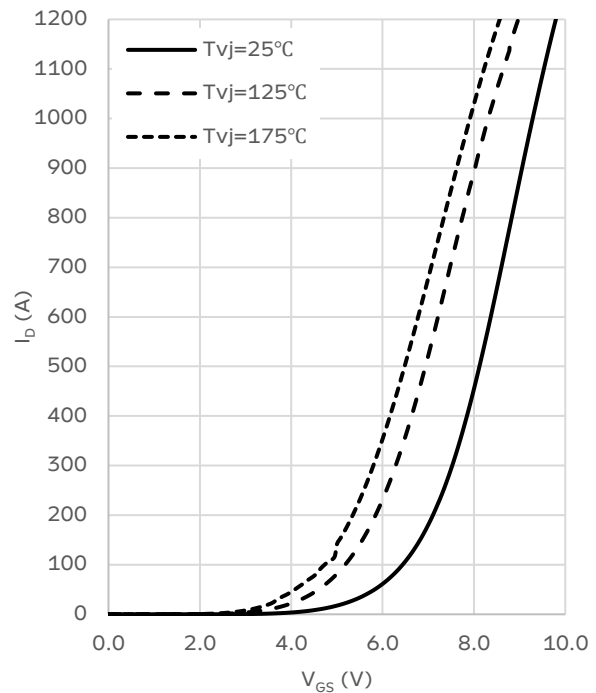
MOSFET on-state characteristics (typical)

$I_D = f(V_{DS})$
 $V_{GS} = 18\text{ V}$



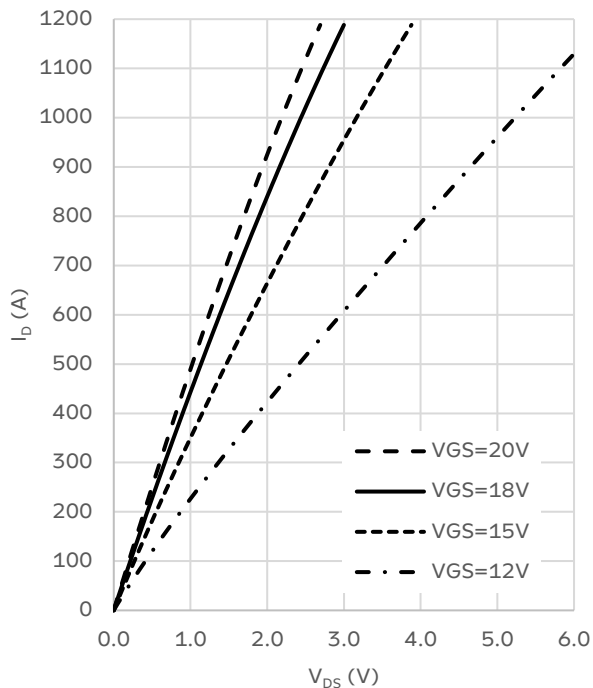
MOSFET transfer characteristics (typical)

$I_D = f(V_{GS})$
 $V_{DS} = 20\text{ V}$



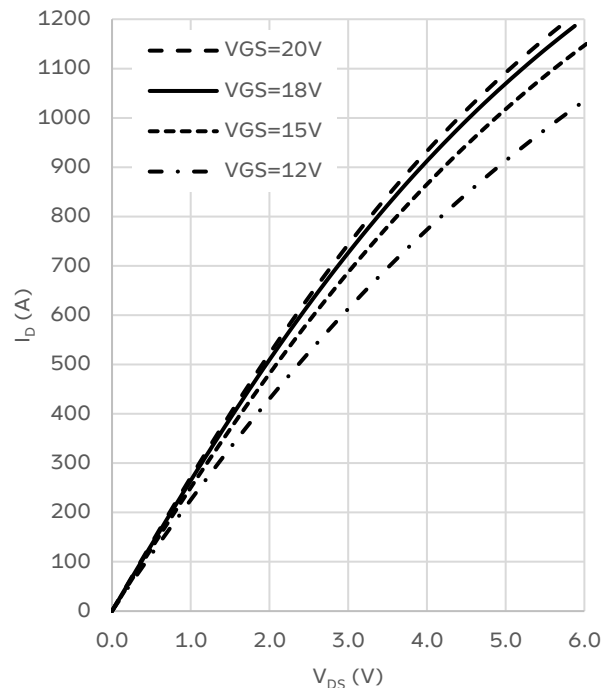
MOSFET output characteristics (typical)

$I_D = f(V_{DS})$
 $T_{vj} = 25^\circ\text{C}$



MOSFET output characteristics (typical)

$I_D = f(V_{DS})$
 $T_{vj} = 175^\circ\text{C}$



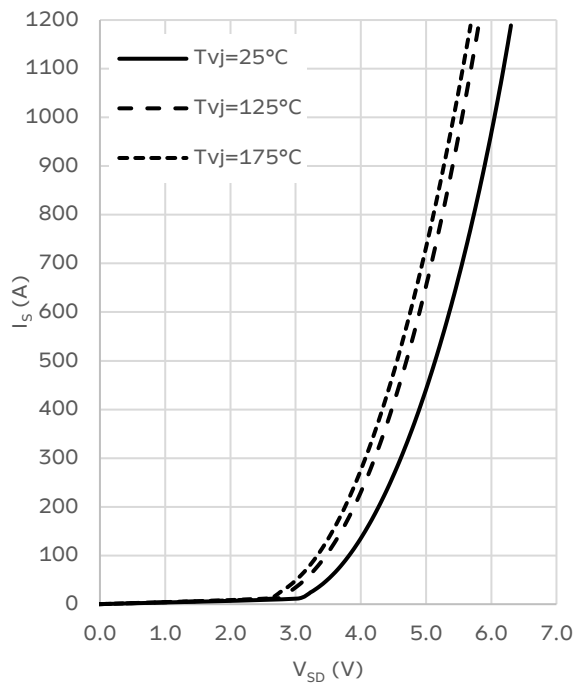


Switching losses (typical)	Switching times (typical)
$E = f(I_D)$ $V_{DS}=800\text{ V}, R_{Gon}=4\text{ }\Omega, R_{Goff}=7\text{ }\Omega, V_{GE}=-5/+18\text{ V}$	$t = f(I_D)$ $V_{DS}=800\text{ V}, R_{Gon}=4\text{ }\Omega, R_{Goff}=7\text{ }\Omega, V_{GE}=-5/+18\text{ V}$
Switching losses (typical)	Switching times (typical)
$E = f(R_G)$ $V_{DS}=800\text{ V}, I=5000\text{ A}, V_{GS}=-5/+18\text{ V}$	$t = f(R_G), T_{vj}=175\text{ }^\circ\text{C}$ $V_{DS}=800\text{ V}, I=500\text{ A}, V_{GS}=-5/+18\text{ V}$

Body diode characteristic (typical)

$I_S = f(V_{SD})$

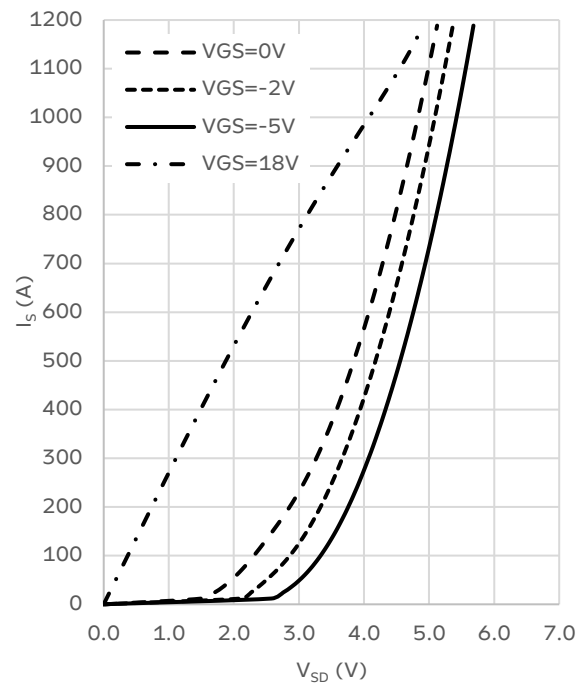
$V_{GS} = -5 \text{ V}$



Body diode characteristic (typical)

$I_S = f(V_{SD})$

$T_{vj} = 175^\circ\text{C}$



Diode switching characteristics (typical)

$E_{rec} = f(I_F)$, $I_{RM} = f(I_F)$

$V_{DC} = 800 \text{ V}$, $R_{Gon} = 4 \Omega$ (MOSFET), $V_{GS} = -4/+18 \text{ V}$

Diode switching characteristics (typical)

$E_{rec} = f(di/dt)$, $I_{RM} = f(di/dt)$

$V_{DC} = 800 \text{ V}$, $I_D = -600 \text{ A}$, $V_{GS} = -5/+18 \text{ V}$ (MOSFET)



Thermal resistance versus flow rate	Transient thermal impedance
$R_{th(J-A)} = f(dv/dt)$	$Z_{th(J-A)} = f(t)$ $T_F = 50^{\circ}C$
<i>tbd</i>	<i>tbd</i>